Application/Control No. Applicant(s)/Patent Under Reexamination 10/048,007 WATANABE ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2618 Yuwen Pan **U.S. PATENT DOCUMENTS** Document Number Date Name Classification Country Code-Number-Kind Code MM-YYYY US-6,745,153 06-2004 White et al. 702/184 * US-6,972,669 12-2005 Saito et al. 340/438 В US-С US-D US-Ε US-F US-G USн US-US-US-Κ US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification MM-YYYY Country Code-Number-Kind Code Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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